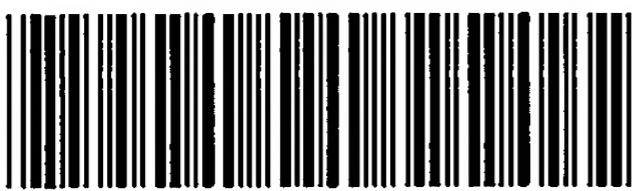


## **Search Notes**



**Application/Control No.**

10/646,709

Examiner

Phat X. Cao

**Applicant(s)/Patent under  
Reexamination**

OHNISHI, SADAYUKI

## **Art Unit**

2814

**SEARCHED**

## **SEARCH NOTES (INCLUDING SEARCH STRATEGY)**

## **INTERFERENCE SEARCHED**

# INTERFERENCE SEARCHED